

## NPN SILICON POWER TRANSISTORS

...designed for use in power amplifier application

### FEATURES:

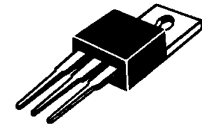
- \* Low Collector-Emitter Saturation Voltage  
 $V_{CE(sat)} = 1.0V(\text{Max}) @ I_C = 3.0A, I_B = 0.3A$
- \* DC Current Gain  
 $hFE = 40-240 @ I_C = 0.5A$
- \* Complementary to PNP 2SB596

**NPN**  
**2SD526**

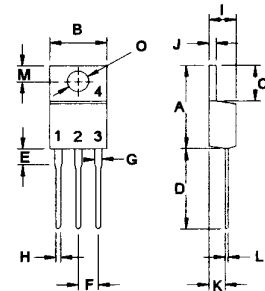
**4 AMPERE**  
**POWER**  
**TRANSISTORS**  
**80 VOLTS**  
**30 WATTS**

### MAXIMUM RATINGS

Characteristic	Symbol	2SD526	Unit
Collector-Emitter Voltage	$V_{CEO}$	80	V
Collector-Base Voltage	$V_{CBO}$	80	V
Emitter-Base Voltage	$V_{EBO}$	5.0	V
Collector Current - Continuous - Peak	$I_C$ $I_{CM}$	4.0 8.0	A
Base current	$I_B$	2.0	A
Total Power Dissipation @ $T_C = 25^\circ\text{C}$ Derate above $25^\circ\text{C}$	$P_D$	30 0.24	W W/ $^\circ\text{C}$
Operating and Storage Junction Temperature Range	$T_J, T_{STG}$	-55 to +150	$^\circ\text{C}$



**TO-220**

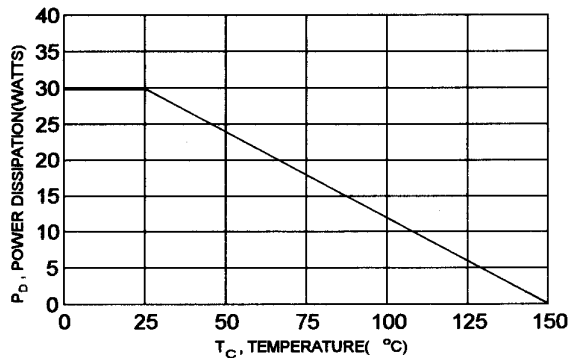


PIN 1.BASE  
2.COLLECTOR  
3.EMITTER  
4.COLLECTOR(CASE)

### THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Thermal Resistance Junction to Case	$R_{\theta jc}$	4.16	$^\circ\text{C}/\text{W}$

**FIGURE -1 POWER DERATING**



DIM	MILLIMETERS	
	MIN	MAX
A	14.68	15.31
B	9.78	10.42
C	5.01	6.52
D	13.06	14.62
E	3.57	4.07
F	2.42	3.66
G	1.12	1.36
H	0.72	0.96
I	4.22	4.98
J	1.14	1.38
K	2.20	2.97
L	0.33	0.55
M	2.48	2.98
O	3.70	3.90

**ELECTRICAL CHARACTERISTICS** (  $T_c = 25^\circ\text{C}$  unless otherwise noted )

Characteristic	Symbol	Min	Max	Unit
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**OFF CHARACTERISTICS**

Collector-Emitter Breakdown Voltage ( $I_C = 50 \text{ mA}$ , $I_B = 0$ )	$V_{(BR)CEO}$	80		V
Emitter-Base Breakdown Voltage ( $I_B = 10 \text{ mA}$ , $I_C = 0$ )	$V_{(BR)EBO}$	5.0		V
Collector Cutoff Current ( $V_{CB} = 80 \text{ V}$ , $I_E = 0$ )	$I_{CBO}$		30	$\mu\text{A}$
Emitter Cutoff Current ( $V_{EB} = 5.0 \text{ V}$ , $I_C = 0$ )	$I_{EBO}$		100	$\mu\text{A}$

**ON CHARACTERISTICS (1)**

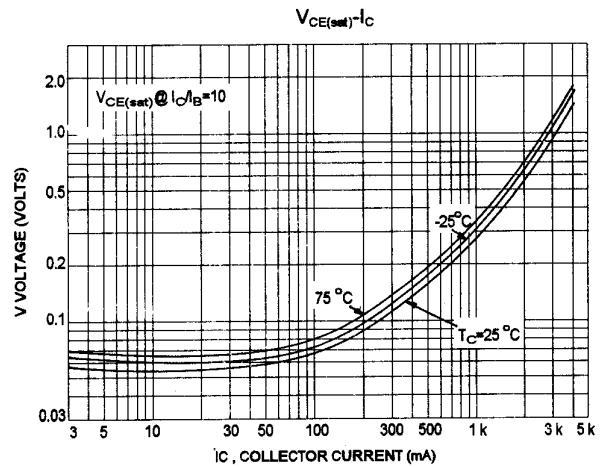
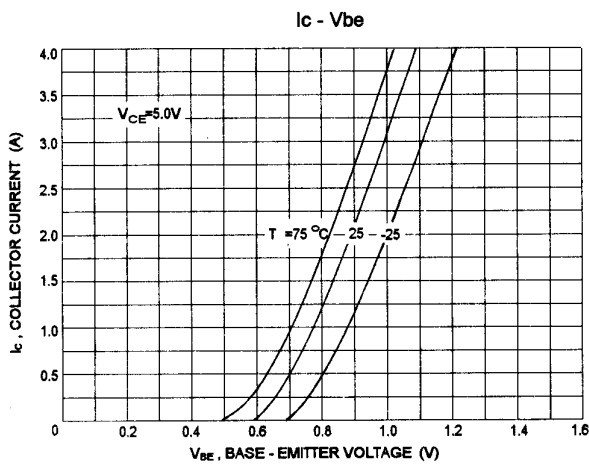
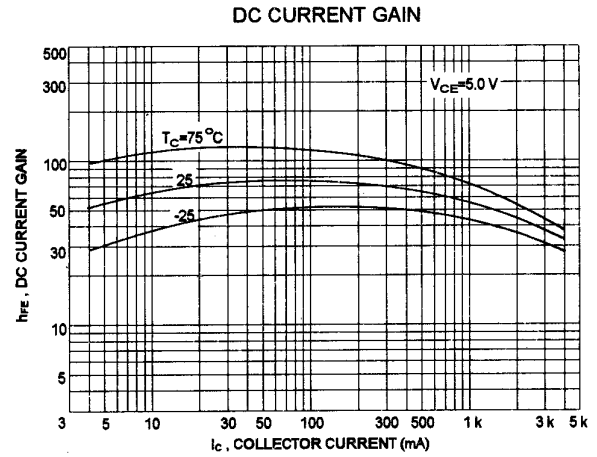
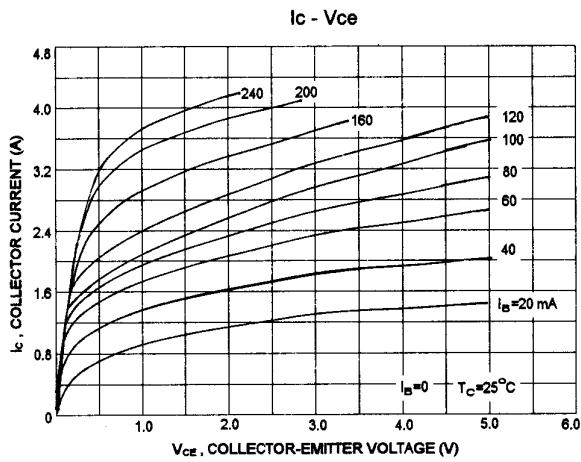
DC Current Gain ( $I_C = 0.5 \text{ A}$ , $V_{CE} = 5.0 \text{ V}$ ) * ( $I_C = 3.0 \text{ A}$ , $V_{CE} = 5.0 \text{ V}$ )	$h_{FE(2)}$ $h_{FE}$	40 15	240	
Collector-Emitter Saturation Voltage ( $I_C = 3.0 \text{ A}$ , $I_B = 300 \text{ mA}$ )	$V_{CE(sat)}$		1.5	V
Base-Emitter On Voltage ( $I_C = 3.0 \text{ A}$ , $V_{CE} = 5.0 \text{ V}$ )	$V_{BE(on)}$		1.5	V

**DYNAMIC CHARACTERISTICS**

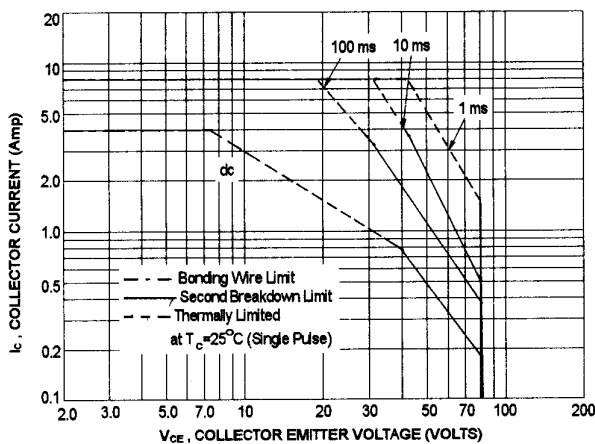
Current-Gain-Bandwidth Product ( $I_C = 0.5 \text{ A}$ , $V_{CE} = 5.0 \text{ V}$ , $f = 1.0 \text{ MHz}$ )	$f_T$	3.0		MHz
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(1) Pulse Test: Pulse Width = 300  $\mu\text{s}$ , Duty Cycle  $\leq 2.0\%$ \*  $h_{FE(2)}$  Classification :

40	R	80	70	O	140	120	Y	240
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**ACTIVE-REGION SAFE OPERATING AREA (SOA)**



There are two limitation on the power handling ability of a transistor: average junction temperature and second breakdown safe operating area curves indicate  $I_c - V_{CE}$  limits of the transistor that must be observed for reliable operation i.e., the transistor must not be subjected to greater dissipation than curves indicate.

The data of SOA curve is base on  $T_{J(PK)} = 150^\circ\text{C}$ ;  $T_C$  is variable depending on conditions. second breakdown pulse limits are valid for duty cycles to 10% provided  $T_{J(PK)} \leq 150^\circ\text{C}$ . At high case temperatures, thermal limitation will reduce the power that can be handled to values less than the limitations imposed by second breakdown.